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Example: optical <and> (fiber <or> fibre) <in> ti
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4) Click Search. See Search Examples

```
vernier<paragraph>
(decompression<or>decompressed
<or>decompressing<or>decompres
s)<and>event
```

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vernier<paragraph>(decompression<or>decompressed Search

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4	DECOMPRESSES
5	DECOMPRESSING
6	DECOMPRESSINGS
7	DECOMPRESSION
8	DECOMPRESSIONS
9	EVENT
10	EVENTS
11	VERNIER
12	VERNIERS
13	((VERNIER SAME (DECOMPRESS OR DECOMPRESSING OR DECOMPRESSED OR DECOMPRESSION)) AND EVENT)

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1	14281							
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3	0							
4	8321							
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6	0							
7	37177							
8	371							
9	879628							
10	218781							
11	13388							
12	670							
13	5							

	U	1	Document ID	Issue Date	Pages	Title	Current OR
1	X		US 20040107058 A1	20040603	51	Event pipeline and summing method and apparatus for event based test system	702/31
2	X		US 6532561 B1	20030311		Event based semiconductor test system	714/738
3	X		US 6226765 B1	20010501	14	Event based test system data memory compression	714/718
4	X		WO 2004008157 A2	20040122	76	EVENT PIPELINE AND SUMMING METHOD AND APPARATUS FOR EVENT BASED TEST SYSTEM	
5	X		WO 2004008157 A	20040122		Event pipeline and vernier summing apparatus for event based semiconductor test system, has pipelines incorporated in event vernier summing logic for processing event vernier data in parallel	

	Current XRef	Retrieval Classif	Inventor	S	C	P	2	3	4	5	Image Doc. Displayed	PT
1			Gomes, Glen et al.								US 20040107058	
2			Turnquist; James Alan et al.									
3	365/201; 714/39; 714/724; 714/741; 714/742		Le; Anthony et al.								US 6226765	
4			GOMES, GOMES et al.								WO 2004008157 A2	
5			GOMES, G et al.									

	Search Terms
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4	DECOMPRESSINGS
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6	DECOMPRESSIONS
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9	LE-ANTHONIES
10	LE-ANTHONY
11	LE-ANTHONYS
12	VERNIER
13	VERNIERS
14	((((GOMES-GLEN.IN.) OR (LE-ANTHONY.IN.)) AND VERNIER) AND (DECOMPRESSING OR DECOMPRESSED OR DECOMPRESSION))

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10	29							
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3			GOMES, GOMES et al.								WO 2004008157 A2	